

May 1995

54F/74F574 Octal D-Type Flip-Flop with TRI-STATE® Outputs

General Description

The 'F574 is a high-speed, low power octal flip-flop with a buffered common Clock (CP) and a buffered common Output Enable (\overline{OE}). The information presented to the D inputs is stored in the flip-flops on the LOW-to-HIGH Clock (CP) transition.

This device is functionally identical to the 'F374 except for the pinouts.

Features

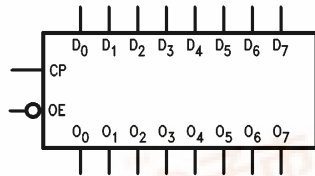
- Inputs and outputs on opposite sides of package allowing easy interface with microprocessors
- Useful as input or output port for microprocessors
- Functionally identical to 'F374
- TRI-STATE outputs for bus-oriented applications

Commercial	Military	Package Number	Package Description
74F574PC		N20A	20-Lead (0.300" Wide) Molded Dual-In-Line
	54F574DM (Note 2)	J20A	20-Lead Ceramic Dual-In-Line
74F574SC (Note 1)		M20B	20-Lead (0.300" Wide) Molded Small Outline, JEDEC
74F574SJ (Note 1)		M20D	20-Lead (0.300" Wide) Molded Small Outline, EIAJ
	54F574FM (Note 2)	W20A	20-Lead Cerpack
	54F574LM (Note 2)	E20A	20-Lead Ceramic Leadless Chip Carrier, Type C

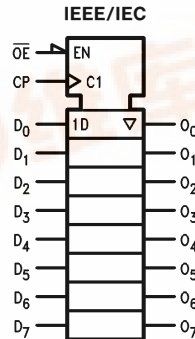
Note 1: Devices also available in 13" reel. Use suffix = SCX and SJX.

Note 2: Military grade device with environmental and burn-in processing. Use suffix = DMQB, FMQB and LMQB.

Logic Symbols



TL/F/9567-1



TL/F/9567-4

Unit Loading/Fan Out

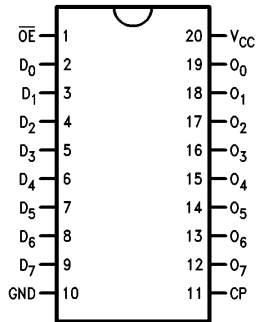
Pin Names	Description	54F/74F	
		U.L. HIGH/LOW	Input I_{IH}/I_{IL} Output I_{OH}/I_{OL}
D ₀ -D ₇	Data Inputs	1.0/1.0	20 μ A/ -0.6 mA
CP	Clock Pulse Input (Active LOW)	1.0/1.0	20 μ A/ -0.6 mA
\overline{OE}	TRI-STATE Output Enable Input (Active LOW)	1.0/1.0	20 μ A/ -0.6 mA
O ₀ -O ₇	TRI-STATE Outputs	150/40 (33.3)	-3 mA/24 mA (20 mA)

TRI-STATE® is a registered trademark of National Semiconductor Corporation.



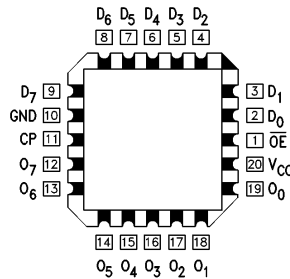
Connection Diagrams

Pin Assignment
for DIP, SOIC and Flatpak



TL/F/9567-2

Pin Assignment
for LCC



TL/F/9567-3

Functional Description

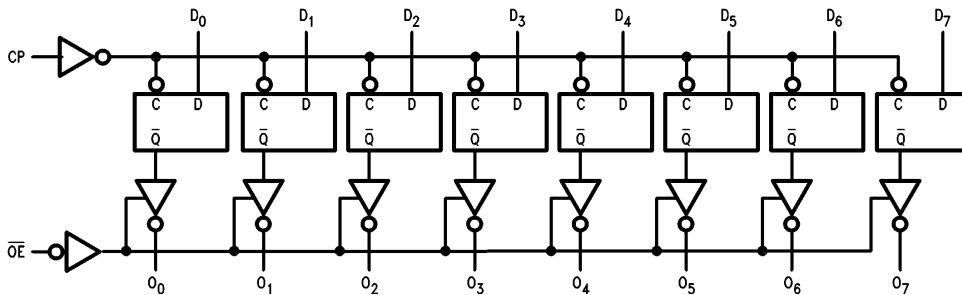
The 'F574 consists of eight edge-triggered flip-flops with individual D-type inputs and TRI-STATE true outputs. The buffered clock and buffered Output Enable are common to all flip-flops. The eight flip-flops will store the state of their individual D inputs that meet the setup and hold times requirements on the LOW-to-HIGH Clock (CP) transition. With the Output Enable (\overline{OE}) LOW, the contents of the eight flip-flops are available at the outputs. When \overline{OE} is HIGH, the outputs go to the high impedance state. Operation of the \overline{OE} input does not affect the state of the flip-flops.

Function Table

Inputs			Internal	Outputs	Function
\overline{OE}	CP	D	Q	O	
H	H	L	NC	Z	Hold
H	H	H	NC	Z	Hold
H	↗	L	L	Z	Load
H	↗	H	H	Z	Load
L	↗	L	L	L	Data Available
L	↗	H	H	H	Data Available
L	H	L	NC	NC	No Change in Data
L	H	H	NC	NC	No Change in Data

H = HIGH Voltage Level
L = LOW Voltage Level
X = Immaterial
Z = High Impedance
↗ = LOW-to-HIGH Transition
NC = No Change

Logic Diagram



TL/F/9567-5

Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Storage Temperature	-65°C to +150°C
Ambient Temperature under Bias	-55°C to +125°C
Junction Temperature under Bias	-55°C to +175°C
Plastic	-55°C to +150°C
V _{CC} Pin Potential to Ground Pin	-0.5V to +7.0V
Input Voltage (Note 2)	-0.5V to +7.0V
Input Current (Note 2)	-30 mA to +5.0 mA
Voltage Applied to Output in HIGH State (with V _{CC} = 0V)	
Standard Output	-0.5V to V _{CC}
TRI-STATE Output	-0.5V to +5.5V

Current Applied to Output in LOW State (Max) twice the rated I_{OL} (mA)

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

Recommended Operating Conditions

Free Air Ambient Temperature	
Military	-55°C to +125°C
Commercial	0°C to +70°C
Supply Voltage	
Military	+4.5V to +5.5V
Commercial	+4.5V to +5.5V

DC Electrical Characteristics

Symbol	Parameter		54F/74F			Units	V _{CC}	Conditions
			Min	Typ	Max			
V _{IH}	Input HIGH Voltage		2.0			V		Recognized as a HIGH Signal
V _{IL}	Input LOW Voltage		0.8			V		Recognized as a LOW Signal
V _{CD}	Input Clamp Diode Voltage		-1.2			V	Min	I _{IN} = -18 mA
V _{OH}	Output HIGH Voltage	54F 10% V _{CC}	2.5			V	Min	I _{OH} = -1 mA
		54F 10% V _{CC}	2.4					I _{OH} = -3 mA
		74F 10% V _{CC}	2.5					I _{OH} = -1 mA
		74F 10% V _{CC}	2.4					I _{OH} = -3 mA
		74F 5% V _{CC}	2.7					I _{OH} = -1 mA
		74F 5% V _{CC}	2.7					I _{OH} = -3 mA
V _{OL}	Output LOW Voltage	54F 10% V _{CC}	0.5			V	Min	I _{OL} = 20 mA
		74F 10% V _{CC}	0.5					I _{OL} = 24 mA
I _{IH}	Input HIGH Current	54F	20.0			μA	Max	V _{IN} = 2.7V
		74F	5.0					
I _{BVI}	Input HIGH Current Breakdown Test	54F	100			μA	Max	V _{IN} = 7.0V
		74F	7.0					
I _{CEX}	Output HIGH Leakage Current	54F	250			μA	Max	V _{OUT} = V _{CC}
		74F	50					
V _{ID}	Input Leakage Test	74F	4.75			V	0.0	I _{ID} = 1.9 μA All Other Pins Grounded
I _{OD}	Output Leakage Circuit Current	74F	3.75			μA	0.0	V _{IOD} = 150 mV All Other Pins Grounded
I _{IL}	Input LOW Current		-0.6			mA	Max	V _{IN} = 0.5V
I _{OZH}	Output Leakage Current		50			μA	Max	V _{OUT} = 2.7V
I _{OZL}	Output Leakage Current		-50			μA	Max	V _{OUT} = 0.5V
I _{OS}	Output Short-Circuit Current		-60	-150		mA	Max	V _{OUT} = 0V
I _{ZZ}	Bus Drainage Test		500			μA	0.0V	V _{OUT} = 5.25V
I _{CCZ}	Power Supply Current		55	86		mA	Max	V _O = HIGH Z

AC Electrical Characteristics

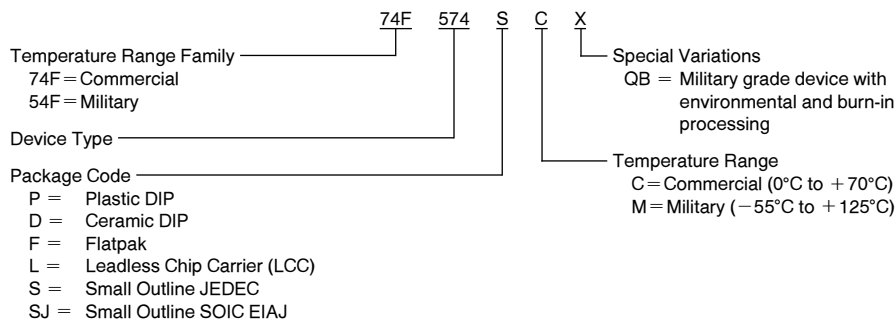
Symbol	Parameter	74F			54F		74F		Units
		T _A = +25°C V _{CC} = +5.0V C _L = 50 pF			T _A , V _{CC} = Mil C _L = 50 pF		T _A , V _{CC} = Com C _L = 50 pF		
		Min	Typ	Max	Min	Max	Min	Max	
f _{max}	Maximum Clock Frequency	100			60		70		MHz
t _{PLH} t _{PHL}	Propagation Delay CP to O _n	2.5	5.3	8.5	2.5	9.5	2.5	8.5	ns
t _{PZH} t _{PZL}	Output Enable Time	3.0	5.5	9.0	2.5	10.5	2.5	10.0	
t _{PHZ} t _{PLZ}	Output Disable Time	1.5	3.3	5.5	1.5	7.0	1.5	6.5	ns
		1.5	2.8	5.5	1.5	7.0	1.5	6.5	

AC Operating Requirements

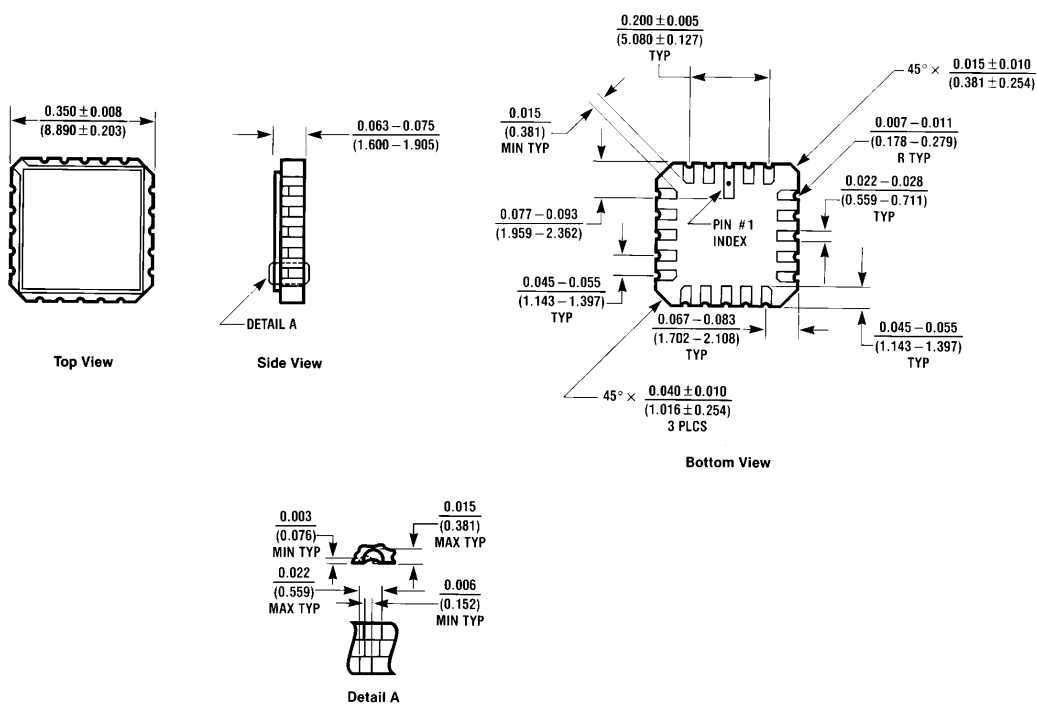
Symbol	Parameter	74F		54F		74F		Units
		T _A = +25°C V _{CC} = +5.0V		T _A , V _{CC} = Mil		T _A , V _{CC} = Com		
		Min	Max	Min	Max	Min	Max	
t _s (H) t _s (L)	Set-up Time, HIGH or LOW D _n to CP	2.5		3.0		2.5		ns
t _h (H) t _h (L)	Hold Time, HIGH or LOW D _n to CP	2.0		2.0		2.0		
t _w (H) t _w (L)	CP Pulse Width HIGH or LOW	5.0		5.0		5.0		ns

Ordering Information

The device number is used to form part of a simplified purchasing code where the package type and temperature range are defined as follows:



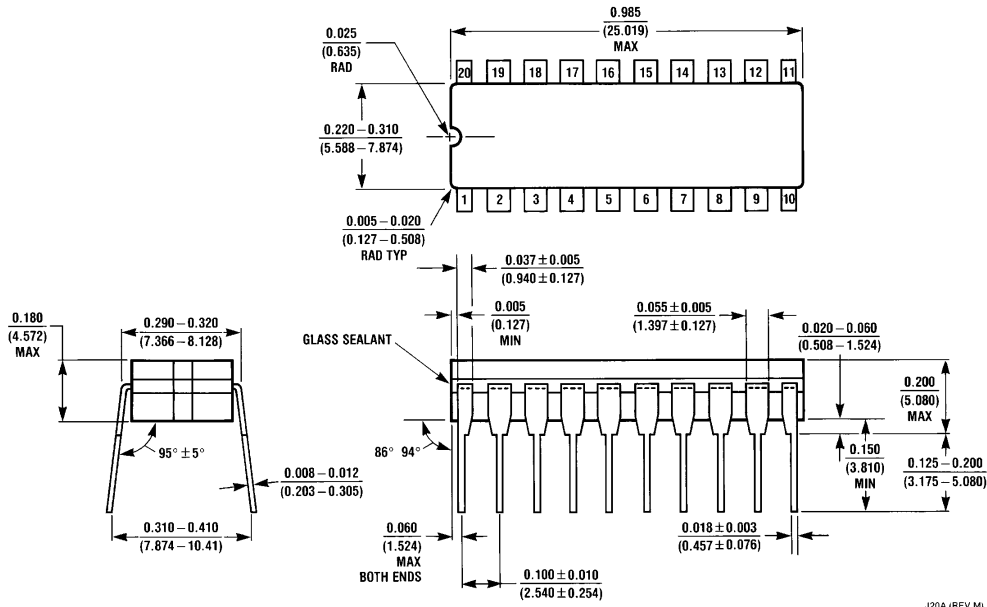
Physical Dimensions inches (millimeters)



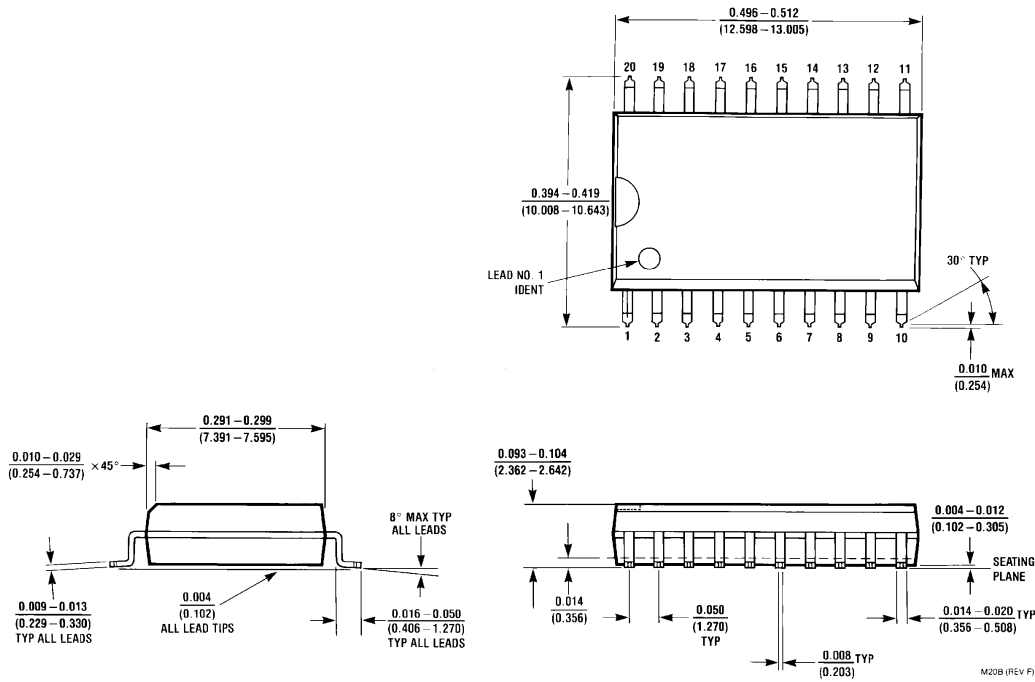
20-Lead Ceramic Leadless Chip Carrier (L)
NS Package Number E20A

E20A (REV D)

Physical Dimensions inches (millimeters) (Continued)

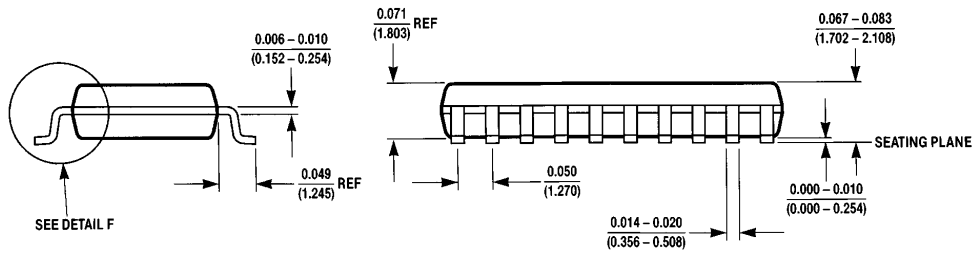
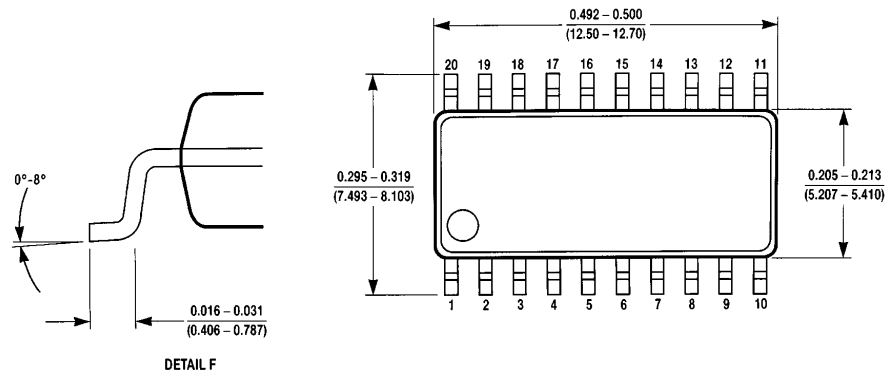


**20-Lead Ceramic Dual-In-Line Package (D)
 NS Package Number J20A**



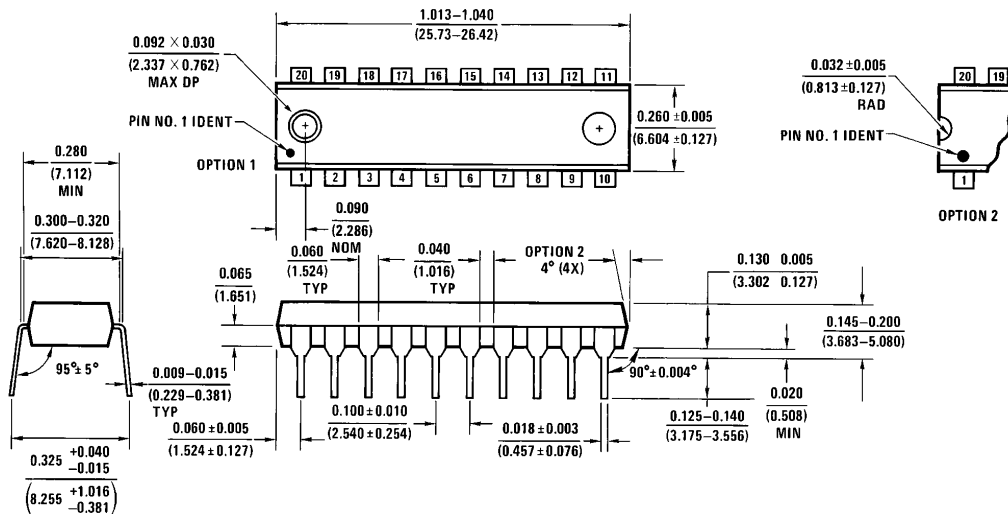
**20-Lead (0.300" Wide) Molded Small Outline Package, JEDEC (S)
 NS Package Number M20B**

Physical Dimensions inches (millimeters) (Continued)



M200 (REV A)

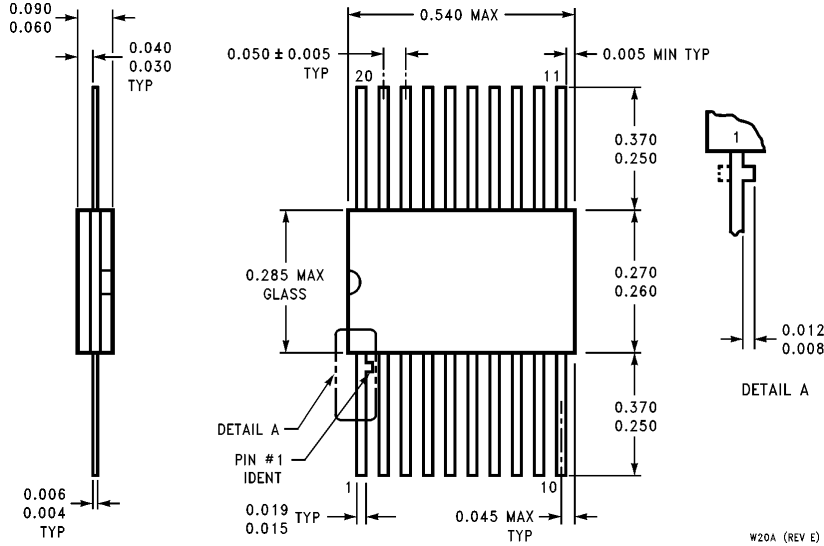
**20-Lead (0.300" Wide) Molded Small Outline Package, EIAJ
NS Package Number M200**



N20A (REV G)

**20-Lead (0.300" Wide) Molded Dual-In-Line Package (P)
NS Package Number N20A**

Physical Dimensions inches (millimeters) (Continued)



LIFE SUPPORT POLICY

NATIONAL'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF THE PRESIDENT OF NATIONAL SEMICONDUCTOR CORPORATION. As used herein:

1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, and whose failure to perform, when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury to the user.
2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.



National Semiconductor Corporation
 2900 Semiconductor Drive
 P.O. Box 58090
 Santa Clara, CA 95052-8090
 Tel: 1(800) 272-9959
 TWX: (910) 339-9240

National Semiconductor GmbH
 Livry-Gargan-Str. 10
 D-82256 Fürstenfeldbruck
 Germany
 Tel: (81-41) 35-0
 Telex: 527649
 Fax: (81-41) 35-1

National Semiconductor Japan Ltd.
 Sumitomo Chemical
 Engineering Center
 Bldg. 7F
 1-7-1, Nakase, Mihama-Ku
 Chiba-City,
 Ciba Prefecture 261
 Tel: (043) 299-2300
 Fax: (043) 299-2500

National Semiconductor Hong Kong Ltd.
 13th Floor, Straight Block,
 Ocean Centre, 5 Canton Rd.
 Tsimshatsui, Kowloon
 Hong Kong
 Tel: (852) 2737-1600
 Fax: (852) 2736-9960

National Semiconductores Do Brazil Ltda.
 Rue Deputado Lacerda Franco
 120-3A
 Sao Paulo-SP
 Brazil 05418-000
 Tel: (55-11) 212-5066
 Telex: 391-1131931 NSBR BR
 Fax: (55-11) 212-1181

National Semiconductor (Australia) Pty, Ltd.
 Building 16
 Business Park Drive
 Monash Business Park
 Nottingham, Melbourne
 Victoria 3168 Australia
 Tel: (3) 558-9999
 Fax: (3) 558-9998

National does not assume any responsibility for use of any circuitry described, no circuit patent licenses are implied and National reserves the right at any time without notice to change said circuitry and specifications.